

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, BIPOLAR, ADVANCED LOW POWER SCHOTTKY TTL,  
AND, OR, NAND, AND NOR GATES, MONOLITHIC SILICON

This amendment forms a part of MIL-M-38510/384(USAF),  
dated 7 December 1983, and is approved for use within the  
Department of the Air Force and is available for use by  
all Departments and Agencies of the Department of Defense.

PAGE 1

Title: Delete and substitute as printed above.

PAGE 2

1.3, thermal resistance, delete and substitute:

"Thermal resistance, junction-to-case ( $\Theta_{JC}$ ):

Cases A, B, C, D, and 2 - - - - - See MIL-M-38510, appendix C".

1.3, junction temperature ( $T_J$ ): Add "2/".

1.4, Recommended operating conditions, add " $V_{CC}$ " after supply voltage.

Add footnote 2/ to bottom of page as follows:

"2/ Maximum junction temperature shall not be exceeded except for allowable short duration burn-in  
screening conditions in accordance with method 5004 of MIL-STD-883".

PAGE 3

Table I, low level output voltage,  $V_{OL}$ , conditions column: Delete " $I_{IN}$ " and substitute " $I_{OL}$ ".

Table I, output current,  $I_O$ , device type 11, min limits column: Delete "-30" and substitute "-20".

PAGE 21

Table III,  $I_O$ , test numbers 45 through 48, min limits column: Delete "-30" and substitute "-20".

PAGE 23

Table III,  $I_O$ , test numbers 45 through 48, min limits column: Delete "-30" and substitute "-20".

PAGE 33

Table III,  $V_{IC}$ , test numbers 11 through 18, max limits column: Delete "1.5" and substitute "-1.5".

Table III,  $I_O$ , test numbers 43 and 44, min limits column: Delete "-30" and substitute "-20".

PAGE 39

Table III,  $I_O$ , test numbers 37 through 42, min limits column: Delete "-30" and substitute "-20".

MIL-H-38510/384(USAF)  
AMENDMENT 1

CONCLUDING MATERIAL

Custodians:  
Air Force - 17

Review activities:  
Air Force - 19, 85, 99  
DLA - ES

Preparing activity:  
Air Force - 17

Agent:  
DLA - ES

(Project 5962-F726)